

10/541583

JC14 Re PCT/PTO 07 JUL 2005  
PATENT  
8074-1061

## IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Yasuhiro OKAMOTO et al.

Conf.

Application No. NEW NATIONAL PHASE

Group

Filed July 7, 2005

Examiner

FIELD-EFFECT TRANSISTOR

**INFORMATION DISCLOSURE STATEMENT  
(SUBMISSION CONCURRENT WITH THE  
FILING OF A NEW PATENT APPLICATION)**

Assistant Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

July 7, 2005

Sir:

Pursuant to 37 C.F.R. §§ 1.97 and 1.98, and in fulfillment of the duty of disclosure under 37 C.F.R. § 1.56, applicant(s) hereby submit(s) an Information Disclosure Statement for consideration by the Examiner.

**I. LIST OF PATENTS, PUBLICATIONS OR OTHER INFORMATION**

The patents, publications, or other information submitted for consideration by the Office are listed on PTO-1449, attached hereto.

**II. COPIES**

- ☐ Copies of the U.S. patents or publications are not submitted since the USPTO has waived their submission for applications filed after June 30, 2003.
- ☒ Submitted herewith is a legible copy of (i) each foreign patent; (ii) each publication or that portion which caused it to be listed; and (iii) all other information or that portion which caused it to be listed.
- ☐ This application is a National Phase of a PCT application. Some or all of the documents listed on the PTO-1449 are not enclosed because they were cited in the International Search Report and copies should have been forwarded from the International Search Authority pursuant to the trilateral agreement between the USPTO, EPO and JPO, or they are U.S. patents or U.S. published applications. If copies are needed, please contact the undersigned.

III. CONCISE EXPLANATION OF THE RELEVANCE  
(check at least one box)

JC14 Rec'd PCT/PTO 07 JUL 2005

a. ☒ **DOCUMENTS IN THE ENGLISH LANGUAGE**

The attached non U.S. patents, non U.S. patent application publications, foreign publications, or other information in the English language do not require a statement of relevancy.

b. ☒ **DOCUMENTS NOT IN THE ENGLISH LANGUAGE**

A concise explanation of the relevance of all patents, publications, or other information listed that is not in the English language is as follows:

Abstracts are provided.

c. ☒ **FOREIGN SEARCH REPORT OR ACTION**

An English language version of the search report or action that indicates the degree of relevance found by the foreign office is attached, thereby satisfying the requirement for a concise explanation. See MPEP 609(A)(3).

d. ☐ **OTHER**

The following additional information is provided for the Examiner's consideration.

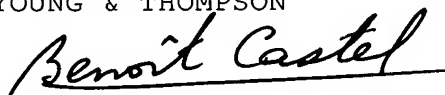
**FEES**

This Information Disclosure Statement is being filed concurrently with the filing of a new patent application; therefore, no fee is required.

If The Examiner has any questions concerning this IDS, he/she is requested to contact the undersigned.

Respectfully submitted,

YOUNG & THOMPSON



Benoit Castel, Reg. No. 35,041  
745 South 23<sup>rd</sup> Street  
Arlington, VA 22202  
Telephone (703) 521-2297  
Telefax (703) 685-0573  
(703) 979-4709

BC/ia

Enclosures: ☒ Form PTO-1449(s)  
☒ Documents  
☒ Foreign Search Report  
☐ Other: \_\_\_\_\_

Application No. **10/5415**  
NEW NATIONAL HAS

Group Art Unit:

[illegible]

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	JP 2000-286428	10/13/2000	JAPAN				
	JP 11-176839	7/2/1999	JAPAN				
	JP 2002-359256	12/13/2002	JAPAN				
	JP 2001-189324	7/10/2001	JAPAN				
	JP 2002-222860	8/9/2002	JAPAN				
	JP 2000-003919	1/7/2000	JAPAN				

	U. K. MISHRA et al., "AlGaIn/GaN HEMTs-An Overview of Device Operation and Applications", Proceedings of the IEEE, Vol. 90, No. 6, June 2002
	J. LI et al., "High breakdown voltage GaN HFET with field plate", ELECTRONICS LETTERS, 1 <sup>st</sup> February 2001, Vol. 37, No. 3
	Y. ANDO et al., "A 110-W AlGaIn/GaN HETEROJUNCTION FET ON THINNED SAPPHIRE SUBSTRATE"

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

\* English language abstract provided for the Examiner's convenience